

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L12	3859	(compress\$6 near15 stress\$6) and (sputter\$6 or Pvd)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 18:22
L14	751	12 and (solder\$6 or bump\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 18:24
L15	561	14 and (@ad<="20010921" or @rlad<="20010921")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 18:24
L16	1807	12 and (Cu or copper)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 18:27
L17	1357	16 and (@ad<="20010921" or @rlad<="20010921")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 18:25
L19	1505	15 or 17	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 18:27
L20	551	19 and ((compress\$6 near15 stress\$6) same (Cu or copper or Ti or titanium or Niv or sputter\$6 or Pvd or adhes\$6))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 18:28

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L6	247	sputter\$6 near20 (compressive adj stress)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 17:11
L7	199	6 and (@ad<="20010921" or @rlad<="20010921")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 17:11

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L21	20565	(Ti or titanium) with sputter\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 20:55
L26	843	(Niv or ((ni or nickel) with (v or vanadium))) with sputter\$6	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 21:12
L27	587	21 and 26	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 21:12
L28	540	27 and (@ad<="20010921" or @rlad<="20010921")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 21:13
L29	257	28 and (Cu or copper)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/02/09 21:13

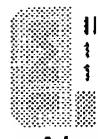
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- 1) Enter a single keyword, phrase, or Boolean expression.
Example: acoustic imaging (means the phrase acoustic imaging plus any stem variations)
- 2) Limit your search by using search operators and field codes, if desired.
Example: optical <and> (fiber <or> fibre) <in> ti
- 3) Limit the results by selecting Search Options.
- 4) Click Search. See [Search Examples](#)

compress* and stress* and
(pvd or sputter*)

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Note: This function returns plural and suffixed forms of the keyword(s).

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